





Editorial

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EuMW 2022 Special Issue

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We live challenging times. It is not the first time. Leonardo da Vinci, the genius of the Renaissance, who inspired the European Microwave Week 2022 logo, the Vitruvian Man, and the motto, “creative microwaves,” lived during the second half of the XV and early XVI century and experienced a world challenged by pandemics, wars, and transformations.

At the same time, it is exactly Leonardo who reminds us that, even during dark hours, science and art, engineering and creativity can, if not even must, remain the sources of light inspiring the world, regardless of borders. They are the constant beacon indicating that a better future is waiting for us, as long as we are able to follow the road painted by Leonardo, who suggests that “Man is the measure of all things.”

We firmly believe that this Special Issue on the *International Journal of Microwave and Wireless Technology* is an exemplifying snapshot on the brilliant ideas mentioned above, collecting some of the best technical contributions we had during the EuMW 2022 in Milan, organized by the European Microwave Association (EuMA), and chaired by Prof. Luca Perregri. These papers virtually cover all domains of the microwave and millimeter spectra, including passive and active devices, systems, integrated circuits, emerging materials, and technologies. All invited manuscripts went through an additional, standard, peer-review, and editorial process.

Overall, they reflect the vibrant atmosphere we had during the EuMW 2022, where starting from hundreds of submissions from all over the world, from Africa to Americas, from Europe to Asia and Oceania, a technical program comprising tens of sessions was built up. In addition, the program was enriched by contributions from keynote speakers, workshops, short courses, forums, focused sessions, and PhD and student schools. Other principal events were the session Women in Microwaves, and the exhibition.

We take the opportunity to thank all authors, reviewers, and Technical Program Committee (TPC) members for making EuMW 2022 such an interesting event. To conclude, we would like to wish you a pleasant reading of this Special Issue and invite you to submit your research results in the *International Journal of Microwave and Wireless Technologies*!